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Attorney Docket No. 49481 (70551)

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

**APPLICANT(S):** M. HATANAKA et al. **EXAMINER:** S. Turner  
**U.S.S.N.:** 09/471,829 **ART UNIT:** 2877  
**FILED:** December 23, 1999  
**TITLE:** APPARATUS AND METHOD FOR MEASURING THE  
**(as amended herein)** THICKNESS OF A THIN FILM VIA THE INTENSITY OF  
REFLECTED LIGHT

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**CERTIFICATE OF MAILING**

I hereby certify that this paper (along with any paper referred to as being attached, enclosed or accompanying) is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to: **Mail Stop AF**, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on May 28, 2004.

By:   
Lee Dunkle

.....  
**Mail Stop AF**  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**AMENDMENT AND RESPONSE TO OFFICE ACTION**  
**PURSUANT TO 37 C.F.R. §1.116**

Sir:

In response to the office action dated April 1, 2004, please consider the following amendments and remarks in favor of the allowance of claims 1 and 3-20 of the above-referenced patent application. Please note that the amendments to the specification and claims commence, respectively, on page 2 and page 3, and the accompanying remarks commence on page 15.